

Enhancement Mode N-Channel Power MOSFET

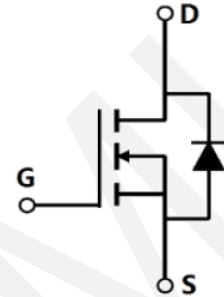
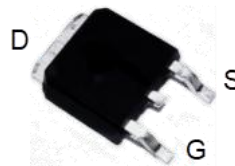
1.Features

- ◆ Low $R_{DS(on)}$ & FOM
- ◆ Extremely low switching loss
- ◆ Excellent stability and uniformity

V_{DS}	$R_{DS(on)}$ Max.	I_D Max.
700V	1.4Ω @ 10V	4.7A

2.Applications

- ◆ PC power
- ◆ LED lighting
- ◆ Telecom power
- ◆ Server power
- ◆ EV Charger
- ◆ Solar/UPS



3.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Value	Units
Drain to Source Voltage	V_{DS}	700	V
Gate to Source Voltage	V_{GS}	±30	V
Drain Current (DC)	I_D	4.7	A
Drain Current (Pulse), $PW \leq 300\mu s$	I_{DP}	12.5	A
Total Dissipation	P_D	24	W
Avalanche Energy, Single Pulsed	E_{AS}	40	mJ
Junction Temperature	T_j	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

4.Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	$R_{\theta JC}$	5.2	°C/W
Junction to ambient	$R_{\theta JA}$	62.5	°C/W

Note 2: When mounted on 1 inch square copper board $t \leq 10\text{sec}$ The value in any given application depends on the user's specific board design.

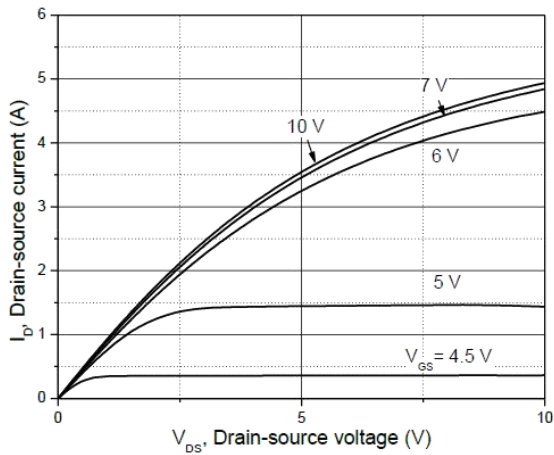
5. Electrical Characteristics at Ta=25°C (Note 3)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu A, V_{GS} = 0V$	650	785		V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650V, V_{GS} = 0V$			1	μA
Gate to Source Leakage Current	I_{GSS}	$V_{GS} = \pm 30V$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	2		5	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 2A, V_{GS} = 10V$	-	1.16	1.4	Ω
Input Capacitance	C_{iss}	$V_{GS}=0V,$ $V_{DS}=50V,$ Frequency=1.0MHz		263.2		pF
Output Capacitance	C_{oss}			18.8		pF
Reverse Transfer Capacitance	C_{rss}			0.83		pF
Turn-ON Delay Time	$t_{d(on)}$			31.3		ns
Rise Time	t_r	$V_{DS} = 560V, I_D = 4A$ $V_{GS} = 10V, R_G = 25\Omega$		17.4		ns
Turn-OFF Delay Time	$t_{d(off)}$			54.3		ns
Fall Time	t_f			36		ns
Total Gate Charge	Q_g		$V_{DS} = 560V,$ $V_{GS} = 10V,$ $I_D = 4A$		7.5	
	Q_{gs}			2.2		nC
	Q_{gd}			3.3		nC
Diode Forward Voltage	V_{FSD}	$I_S = 5A, V_{GS} = 0$		0.88	1.3	V

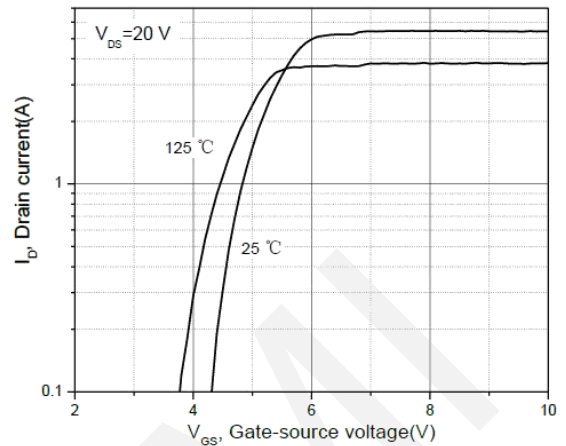
Note 3 : Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



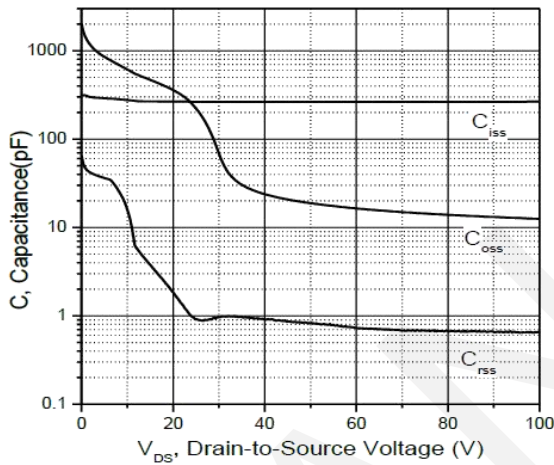
6. Typical electrical and thermal characteristics



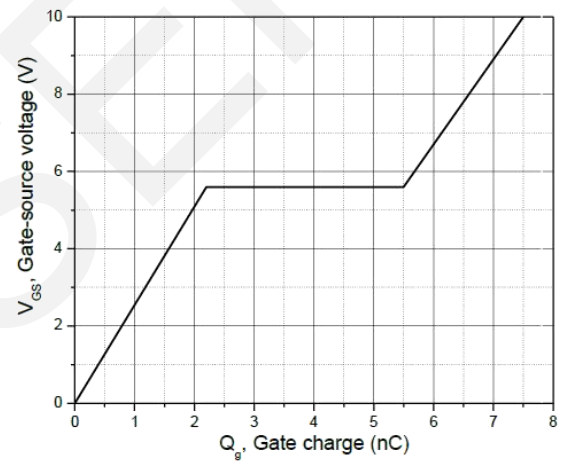
Output Characteristics



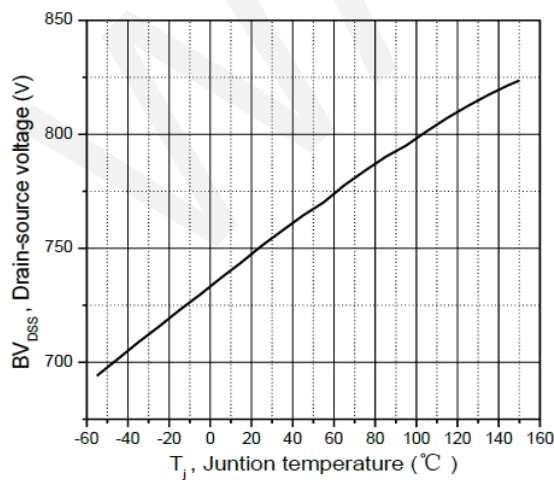
Transfer Characteristics



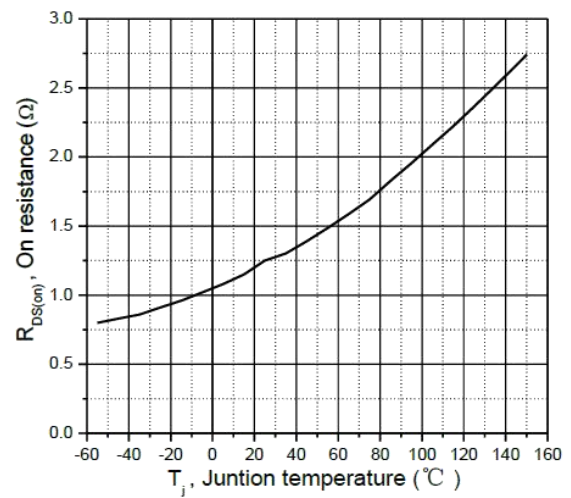
Capacitance



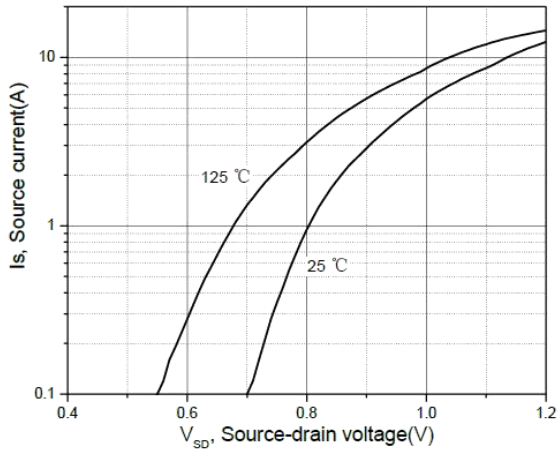
Gate Charge



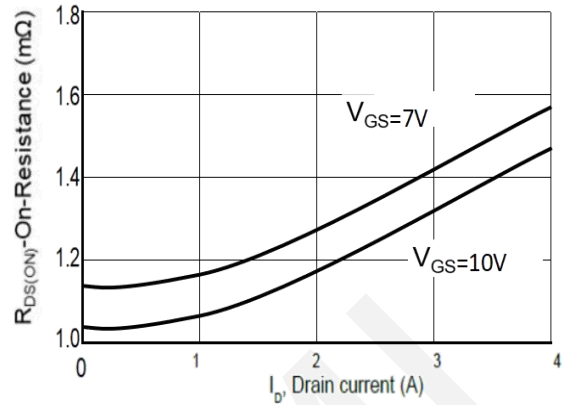
Drain-source breakdown voltage



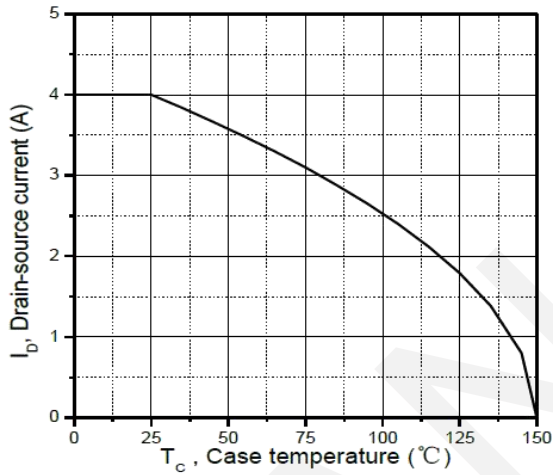
Drain-source on-state resistance



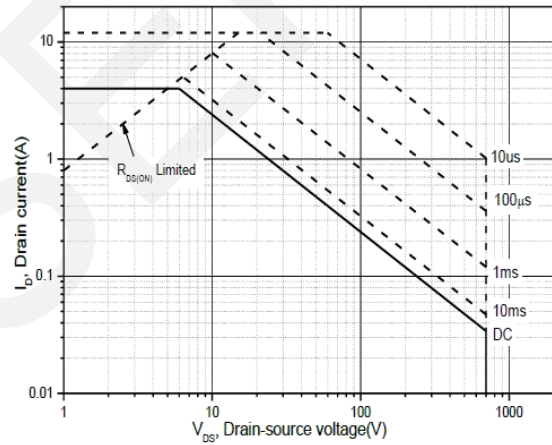
Forward characteristic of body diode



Drain-source on-state resistance



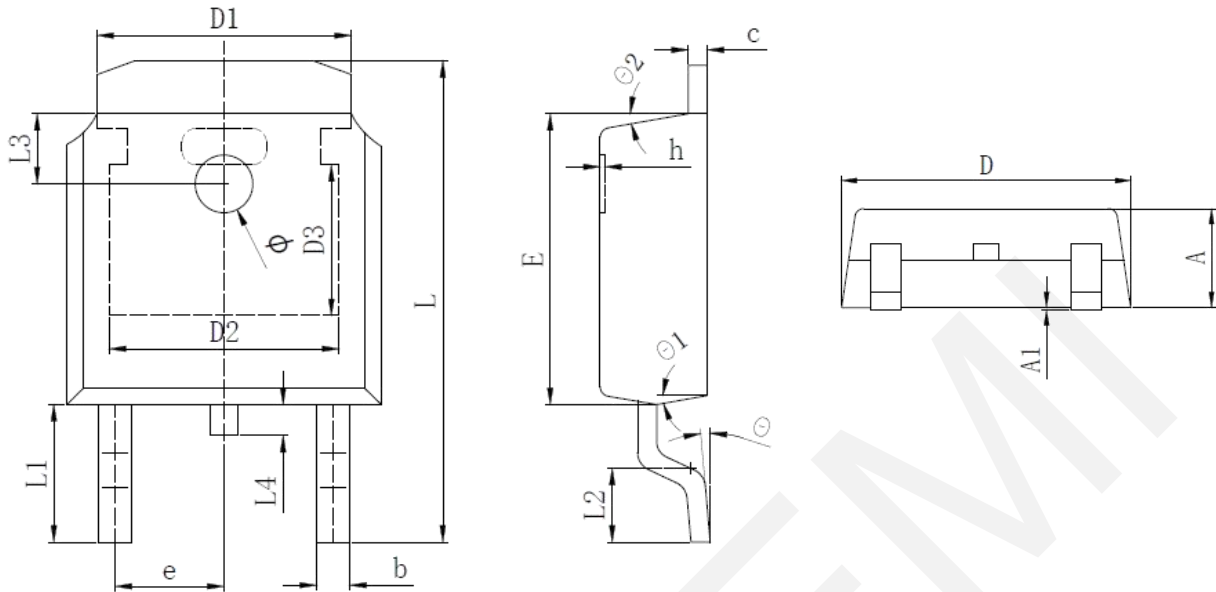
Drain current



Safe operation area $T_C=25^\circ C$



7.Package Dimensions



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	2.200	2.300	2.400
A1	0.000		0.127
b	0.640	0.690	0.740
c(电镀后)	0.460	0.520	0.580
D	6.500	6.600	6.700
D1	5.334 REF		
D2	4.826 REF		
D3	3.166 REF		
E	6.000	6.100	6.200
e	2.286 TYP		
h	0.000	0.100	0.200
L	9.900	10.100	10.300
L1	2.888 REF		
L2	1.400	1.550	1.700
L3	1.600 REF		
L4	0.600	0.800	1.000
φ	1.100	1.200	1.300
θ	0°		8°
θ 1	9° TYP		
θ 2	9° TYP		

8. Important Notice

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